

CHEAT SHEET STAT111

Statistical Methods – Tommy Odland – Last edit: June 13, 2018

▷ Basics

- The **conditional distribution** of Y given X is

$$f_{Y|X}(y|x) = \frac{f(x, y)}{f_X(x)}.$$

- It can be shown that $E[Y] = E_x \left[E[Y|X] \right]$.
- The **marginal distribution** is $f_X(x) = \int f(x, y) dy$.
- The **variance** of a sum is given by

$$V \left[\sum_i a_i X_i \right] = \sum_i \sum_j a_i a_j \text{Cov}[X_i, X_j].$$

- The **correlation** ρ_{XY} is a scaled covariance:

$$\rho_{XY} = \frac{\sigma_{XY}}{\sigma_X \sigma_Y}, \text{ where } \sigma_{XY} = \text{Cov}[X_i, X_j].$$

- The expected value is $E[h(x)] = \int p(x)h(x) dx$.
- A useful shortcut is $V[X] = E[X^2] - E[X]^2$.
- When the **skew** $E[(X - \mu)^3]/\sigma^3$ is positive, the right tail is longer or fatter.

▷ Probability functions

- If a cont. mapping $Y = g(X)$ is monotonic with inverse $X = h(Y)$, then $f_Y(y) = f_X(x) |h'(y)|$.
- The generalization uses the Jacobian $|\det \frac{\partial(x)}{\partial(y)}|$.
- The r 'th order moment of X is $E[X^r]$.
- The **moment generating function** (MGF) of X is defined as $M_X(t) = E[e^{tX}]$.
- It uniquely defines $f(x)$ if it's valid for a range including zero.
- Defines the moments by $\partial_t^r M_X(t)|_{t=0} = E[X^r]$.
- If $R_X(t) = \ln M_X(t)$, then $\mu = R'_X(0)$ and $\sigma = R''_X(0)$.
- $Y = \sum_i a_i X_i$, iff $M_Y(t) = \prod_i M_{X_i}(a_i t)$

- **Discrete probability mass functions**

- $\exp(\lambda) = \lambda e^{-\lambda x}$, $x \geq 0$
- $\text{poisson}(\lambda) = \lambda^x e^{-\lambda}/x!$, $x \geq 0$

- **Continuous probability density functions**

- The gamma function is $\Gamma(k) = \int_0^\infty x^{k-1} e^{-x} dx$.
- $\text{norm}(\mu, \sigma) = \exp(-(x - \mu)^2/2\sigma^2)/\sqrt{2\pi}\sigma$
- X is lognormally distributed if $\log(X) \sim \text{norm}$.
- The Weibull distribution is defined for $x \geq 0$ as

$$f(x; \alpha, \beta) = \frac{\alpha}{\beta^\alpha} x^{\alpha-1} \exp(-(x/\beta)^\alpha),$$

where α is a location parameter, β is a scale parameter and $f(x; \alpha, \beta)$ may be shifted too.

- The student-t distribution is the distribution of

$$T = \frac{Z}{\sqrt{X/\nu}} \cong \frac{\bar{X} - \mu}{S/\sqrt{n}},$$

where $Z \sim \text{norm}$ and $X \sim \chi_\nu^2$.

- The Chi-squared distribution is the distribution of a sum of standard normals, i.e. $\chi_\nu^2 = Z_1^2 + \dots + Z_\nu^2$.
- The f-squared distribution is the distribution of

$$F = \frac{\chi_{\nu_1}^2/\nu_1}{\chi_{\nu_2}^2/\nu_2}.$$

- The standard beta distribution on $[0, 1]$ is

$$f(x; \alpha, \beta) = \frac{\Gamma(\alpha + \beta)}{\Gamma(\alpha)\Gamma(\beta)} x^{\alpha-1} (1-x)^{\beta-1}$$

▷ Order statistics

- The order statistics of X_1, \dots, X_n is obtained by sorting the random variables, yielding Y_1, \dots, Y_n .
- The CDF of Y_1 (smallest value) is

$$P(Y_1 < y) = 1 - [1 - P(Y < y)]^n$$

- The CDF of Y_n (largest value) is

$$P(Y_n < y) = [P(Y \leq y)]^n$$

- The joint pdf of Y_1, \dots, Y_n is given by

$$g(y_1, \dots, y_n) = n! f(y_1) \times \dots \times f(y_n).$$

▷ Point estimation and CIs

- A point estimate $\hat{\theta}$ is a sample based value for θ .
- **Moment estimators** equate theoretical moments $E[X^r] = \int f(x)x^r dx$ with sample moments $n^{-1} \sum_i X_i^r$ to estimate θ . Simple, often biased.
- Three criteria for choosing $\hat{\theta}$:
 - No bias, choose $E[\hat{\theta}] = \theta$.
 - If no bias, choose minimum variance $V[\hat{\theta}]$.
 - Trade-off between bias and variance: $\min_{\hat{\theta}} \text{MSE}$.
- **The mean squared error** of an estimator is $\text{MSE}[\hat{\theta}] = E[(\hat{\theta} - \theta)^2] = V[\hat{\theta}] + E[\hat{\theta} - \theta]^2 = \text{var} + \text{bias}^2$
- Confidence interval for μ when σ is known:

$$\mu \pm z_{\alpha/2} \frac{\sigma}{\sqrt{n}}$$

- Confidence interval for μ when σ is unknown:

$$\mu_0 \pm t_{\alpha/2, n-1} \frac{s}{\sqrt{n}}$$

- Confidence interval for σ^2 :

$$\frac{(n-1)s^2}{\chi_{\alpha/2, n-1}^2} < \sigma^2 < \frac{(n-1)s^2}{\chi_{1-\alpha/2, n-1}^2}$$

- Two approaches to **bootstrap** CI for \bar{x} :
 - Use $\bar{x} \pm z_{\alpha/2} s_b$, where $s_b^2 = \sum_i^n (\bar{x}_i^* - \bar{x}^*)^2 / (n-1)$
 - Bootstrap, compute $n \bar{x}_i^*$'s, use percentiles.

▷ Tests

- In a ***z*-test for differences**, the hypothesis is that $\mu_1 - \mu_2 = \Delta_0$, and σ_1 and σ_2 are both known. Combine standard deviations and test with *z*-test. Either *X* and *Y* are normal, or CLT applies.
- In a ***t*-test for differences**, the hypothesis is that $\mu_1 - \mu_2 = \Delta_0$, and $\sigma_{1,2}$ are both unknown. Combine s_1 and s_2 and use *t*-test. Degrees of freedom is found in an involved expression.
 - If $\sigma_1 = \sigma_2$, but both are unknown, pool them

$$S_p^2 = \frac{m-1}{m+n-2} s_1^2 + \frac{n-1}{m+n-2} s_2^2,$$

and employ a *t*-test with $m+n-2$ df.

- A **Type I** error is rejecting H_0 when H_0 is true. A **Type II** error is keeping H_0 when H_0 is false.
- The power function is $\beta(\mu) = P_\mu(\text{rejecting } H_0)$.

▷ ANOVA

- In one-way **ANOVA**, the hypotheses are

$$H_0 : \mu_1 = \mu_2 = \dots = \mu_I$$

$$H_0 : \text{at least 1 } \mu_i \neq \mu_j$$

Assumes normal distributions and same variance.

- The sum of squares are

$$\text{SSTr} = J \sum_i (\bar{Y}_i - \bar{Y}.)^2 \quad (\text{between-group})$$

$$\text{SSE} = \sum_i \sum_j (Y_{ij} - \bar{Y}_i.)^2 \quad (\text{within-group})$$

$$\text{SST} = \text{SSTr} + \text{SSE} \quad (\text{total})$$

$$\text{MSTr} = \frac{\text{SSTr}}{I-1} \quad \text{MSE} = \frac{\text{SSE}}{I(J-1)} \quad f = \frac{\text{MSTr}}{\text{MSE}}$$

- The ratio is distributed as $f \sim F_{I-1, I(J-1)}$
- Under the null hypothesis, $\text{SSTr} \sim \chi_{I-1}^2$, $\text{SSE} \sim \chi_{I(J-1)}^2$ and $\text{SST} \sim \chi_{I(J-1)}^2$.
- To test for differences, sort μ_i 's, form the interval

$$\bar{x}_i. - \bar{x}_j. \pm Q_{\alpha, I, I(J-1)} \sqrt{\text{MSE}/J}$$

and extend lines to test for significant differences.

▷ Regression

- Assume $y_i = \beta_0 + \beta_1 x_i + \epsilon_i$, where ϵ_i are i.i.d. standard normals.
 - Implies $E[\epsilon_i] = 0$, $V[\epsilon] = \sigma^2$ and independence.
- $S_{xx} = \sum_i (x_i - \bar{x})^2 = \sum_i x_i^2 - n^{-1} (\sum_i x_i)^2$
- In $y = \hat{\beta}_0 + \hat{\beta}_1 x$, we compute $\hat{\beta}_1$ and $\hat{\beta}_0$ as:
 - $\hat{\beta}_1 = S_{xy}/S_{xx}$ and $\hat{\beta}_0 = \bar{y} - \bar{x}\hat{\beta}_1$
- The coefficient of determination r^2 is given by

$$r^2 = 1 - \frac{\text{SSE}}{\text{SST}} = 1 - \frac{\sum_i (y_i - \hat{y}_i)^2}{\sum_i (y_i - \bar{y})^2} = 1 - \frac{\text{res. } \sigma^2}{\text{tot. } \sigma^2}$$

The empirical correlation is $\rho = \sqrt{r^2}$.

- Interference about $\hat{\beta}_1$, i.e. $\hat{\beta}_1 \pm t_{\alpha/2, n-2} s_{\hat{\beta}_1}$.
 - $V[\hat{\beta}_1] = \sigma_{\hat{\beta}_1}^2 = \sigma^2/S_{xx}$, where $\sigma^2 = \text{SSE}/(n-2)$.
- Sample correlation coefficient: $S_{xy}/(\sqrt{S_{xx}}\sqrt{S_{yy}})$.
- **Confidence interval** - interference of $\mu_{Y|X}$, which is deterministic. **Prediction interval** - interference of future *Y* values, which is stochastic.

▷ Goodness-of-fit tests

- **Goodness-of-fit** tests are based on

$$\chi^2 = \sum_i \frac{(\text{obs}_i - \text{expected}_i)^2}{\text{expected}_i} \quad (\text{valid if } np_i \geq 5)$$

which has $\sim \chi_{n-1-m}^2$ degrees of freedom (m is the number of estimated parameters used to compute p_i), or alternatively $\sim \chi_{(I-1)(J-1)}^2$ if it's a contingency table.

▷ Nonparametrics

- The **Wilcoxon signed rank test** has $H_0 : \mu = \mu_0$. Subtract μ_0 , rank the data by absolute value, then re-assign the signs. If H_0 is true, the sum of the positive ranks S_+ should be relatively small. Assumes symmetric distribution.
- The **Wilcoxon ranked sum test** has $H_0 : \mu_A = \mu_B$. Assume m data points from *A* and n from *B*. Concatenate data, rank it, and sum ranks W associated with data from *A*. If H_0 is true, W will be somewhere in the middle of

$$\frac{m(m+1)}{2} \leq W \leq \frac{n(n+2m+1)}{2}$$

Assumes identical distribution shapes.

▷ References

- Jay L. Devore. *Modern Mathematical Statistics with Applications*. 2nd ed. Springer Texts in Statistics. Dordrecht: Springer, 2011.